



Contribution ID: 117 Contribution code: WEP047

Type: Poster Presentation

## Investigating Dirac semimetal cadmium arsenide as a potential low-MTE photocathode

Wednesday 13 August 2025 16:00 (2 hours)

We report on the quantum efficiency (QE) and mean transverse energy (MTE) of photoemitted electrons from cadmium arsenide ( $\text{Cd}_{\text{3}}\text{As}_2$ ), a three-dimensional Dirac semimetal (3D DSM) of interest for photocathode applications due to its unique electronic band structure, characterized by a 3D linear dispersion relation at the Fermi energy. Samples were synthesized at the National Renewable Energy Laboratory (NREL) and transferred under ultra-high vacuum to Arizona State University (ASU) for measurement using a photoemission electron microscope (PEEM). The maximum QE was measured to be 3.37 times;  $10^{-4}$  at 230 nm, and the minimum MTE was 55.8 meV at 250 nm. These findings represent the first reported QE and MTE measurements of  $\text{Cd}_{\text{3}}\text{As}_2$  and are an important step in evaluating the viability of 3D DSMs as low-MTE photocathodes. Such photocathodes, constrained to lower MTEs by the electronic band structure, may prove effective in advancing beam brightness in next-generation instruments and techniques.

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Yes

**Would you like to submit this poster in student poster session on Sunday (August 10th)**

Yes

**Footnotes**

**Funding Agency**

**I have read and accept the Privacy Policy Statement**

Yes

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**Session Classification:** WEP: Wednesday Poster Session

**Track Classification:** MC3 - Novel Particle Sources, Acceleration Techniques, and their Applications